Search Notes			

Application	on/Control No.	Applicant(s)/Patent Reexamination	under
10/754,5	94	ONO ET AL.	
Examine	•	Art Unit	
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SEARCHED			
Class	Subclass	Date	Examiner
438	706	9/7/05	Ku
438	710	1	
438	714		
438	723		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	706	1-/-3/05	
438	710		
438	723		
156	67		
216	74	12/23/1-	Kee

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Keywords search USPAT, USPG-pab. Eps, JPS, Derwent 78M-TDR inventor search	9/2/	kec
peruse parent applications	9/1/5	Kci
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